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Applicant(s): . Masahiro ISHIDA et al.

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T. NGUYENGroup Art Unit  
2829Invention: **METHOD AND APPARATUS FOR DEFECT ANALYSIS OF SEMICONDUCTOR INTEGRATED CIRCUIT**

I hereby certify that the following correspondence:

Reply Under 37 CFR 1.111

(Identify type of correspondence)

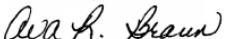
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